

THz generation control in Ta/Fe/Ru/Ni spintronic emitters

R. Adam^{1,a}, C. Greb^{1,2}, D. E. Bürgler¹, D. Cao^{1,3}, S. Heidtfield^{1,2}, J. Cheng⁴, I. Komissarov^{4,5}, H. Hardtdegen⁶, M. Mikulics⁶, M. Büscher^{1,7}, Roman Sobolewski^{4,5}
and C. M. Schneider^{1,2,8}

¹*Peter Grünberg Institute (PGI-6), Research Centre Jülich, Jülich, Germany*

²*Faculty of Physics, University Duisburg-Essen, Duisburg, Germany*

³*College of Physics, Qingdao University, Qingdao, China*

⁴*Dept. of Electrical and Computer Engineering, University of Rochester, Rochester, New York, USA*

⁵*Laboratory for Laser Energetics, University of Rochester, Rochester, New York, USA*

⁶*Ernst Ruska Centre (ERC-2), Research Centre Jülich, Jülich, Germany*

⁷*Inst. für Laser- und Plasmaphysik, Heinrich Heine Universität Düsseldorf, Düsseldorf, Germany*

⁸*Department of Physics, University of California Davis, Davis, California, USA*

^{a)}*Corresponding author: r.adam@fz-juelich.de*

Abstract. Optical laser pulses impinging at ferromagnet/metal thin film stacks can generate picosecond electromagnetic transients with a frequency content extending into the THz range [1-3]. We fabricated Si/SiO₂/Ta/Fe/Ru/Ni/Al₂O₃ THz emitters in which we varied the magnetization alignment of Fe and Ni layers by interlayer exchange coupling (IEC) using different Ru layer thicknesses (t_{Ru}). Depending on IEC, magnetizations of Fe and Ni show either parallel or anti-parallel relative alignment at $t_{\text{Ru}} = 1.1$ nm and $t_{\text{Ru}} = 1.3$ nm, respectively. As a result, THz emission shows a dramatic variation of amplitude with sub-nanometer changes of t_{Ru} in weak external magnetic fields due to an interference of THz transients generated at the individual Fe/Ru and Ru/Ni emitters. We explore the effect of the ambient temperature and Ru thickness variations on the THz amplitude.

REFERENCES

1. R. Adam et al., npj Spintronics **2**, 58 (2024).
2. J. Cheng et al., J. Magn. Magn. Mater., **593**, 171641 (2024).
3. R. Adam et al., Appl. Phys. Lett. **114**, 212405-1-5 (2019).